

May 2001

FQP95N03L

30V LOGIC N-Channel MOSFET

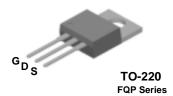
General Description

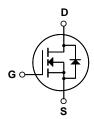
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

Features

- 95A, 30V, $R_{DS(on)}$ = 0.0085 Ω @V_{GS} = 10 V Low gate charge (typical 36 nC)
- Low Crss (typical 240 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP95N03L	Units
V _{DSS}	Drain-Source Voltage		30	V
I _D	Drain Current - Continuous (T _C = 25	°C)	95	А
	- Continuous (T _C = 100°C)		67.2	А
I _{DM}	Drain Current - Pulsed	(Note 1)	380	А
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	400	mJ
I _{AR}	Avalanche Current	(Note 1)	95	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	15	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _C = 25°C)		150	W
	- Derate above 25°C		1.0	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.0	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced 25°C	to		0.03		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 30 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 24 V, T _C = 150°C				10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1.0		2.5	V
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 47.5 \text{ A}$			0.0069	0.0085	\ <u>-</u>
'`DS(on)	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 47.5 \text{ A}$			0.009	0.0115	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 15 V, I _D = 47.5 A	(Note 4)		57		S
Dvnam	ic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz			1750	2280	pF
C _{oss}	Output Capacitance				1080	1400	pF
C _{rss}	Reverse Transfer Capacitance				240	310	pF
Switchi	ing Characteristics		1		I		
t _{d(on)}	Turn-On Delay Time				25	60	ns
t _r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, I_{D} = 47.5 \text{ A},$ $R_{G} = 25 \Omega$			250	510	ns
t _{d(off)}	Turn-Off Delay Time				18	45	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		135	280	ns
Q _g	Total Gate Charge	V _{DS} = 24 V, I _D = 95 A,			36	47	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$			13.4		nC
Q _{gd}	Gate-Drain Charge		Note 4, 5)		17.6		nC
	Source Diode Characteristics ar	nd Maximum Ratings	S				
I _S	Maximum Continuous Drain-Source Diode Forward Current				95	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current				380	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 95 \text{ A}$				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 95 \text{ A},$			55		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs	(Note 4)		65		nC

- Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. L = 45µH, I_{AS} = 95A, V_{DD} = 15V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} ≤ 95A, I_{A} (rdt ≤ 300A/us, V_{DD} ≤ I_{AS} 0 Starting I_{AS} 1 = 25°C 4. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature 6. Continuous Drain Current Calculated by Maximum Junction Temperature: Limited by Package

Typical Characteristics

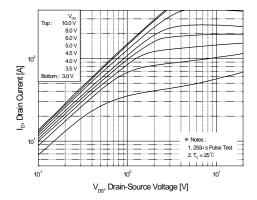


Figure 1. On-Region Characteristics

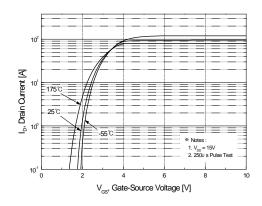


Figure 2. Transfer Characteristics

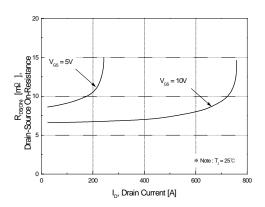


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

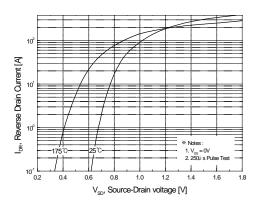


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

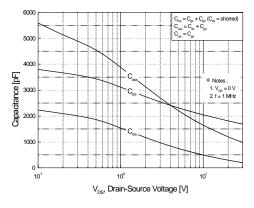


Figure 5. Capacitance Characteristics

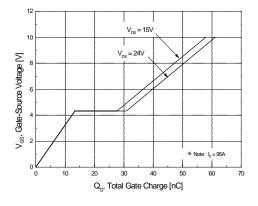
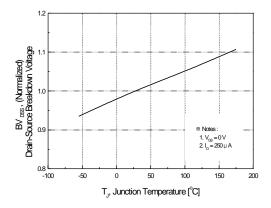


Figure 6. Gate Charge Characteristics

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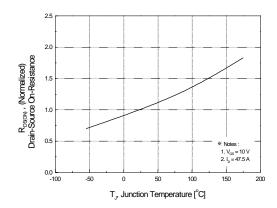
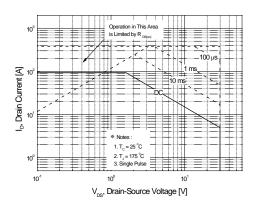


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



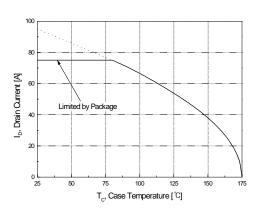


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

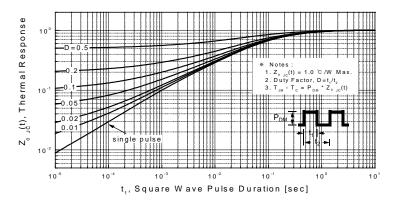
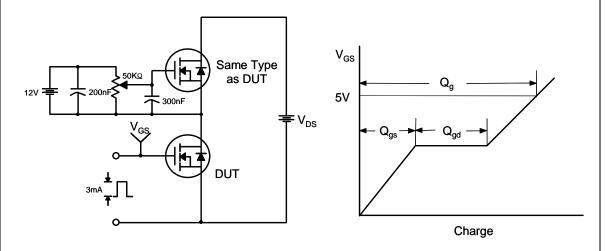


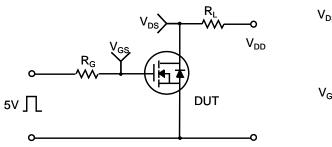
Figure 11. Transient Thermal Response Curve

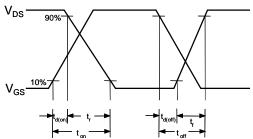
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Gate Charge Test Circuit & Waveform

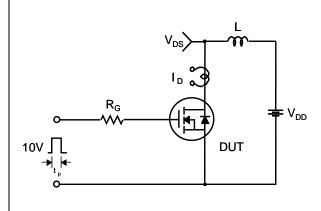


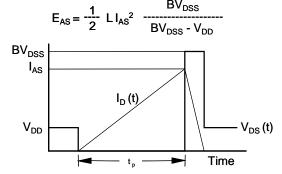
Resistive Switching Test Circuit & Waveforms



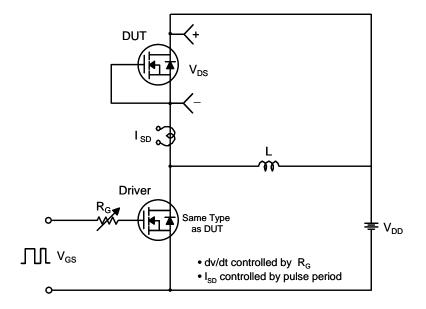


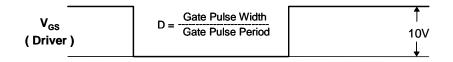
Unclamped Inductive Switching Test Circuit & Waveforms

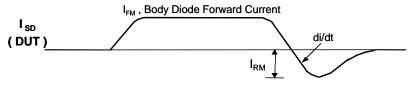




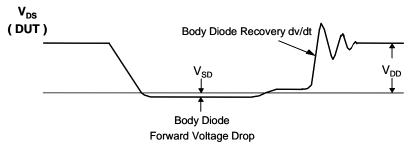
Peak Diode Recovery dv/dt Test Circuit & Waveforms

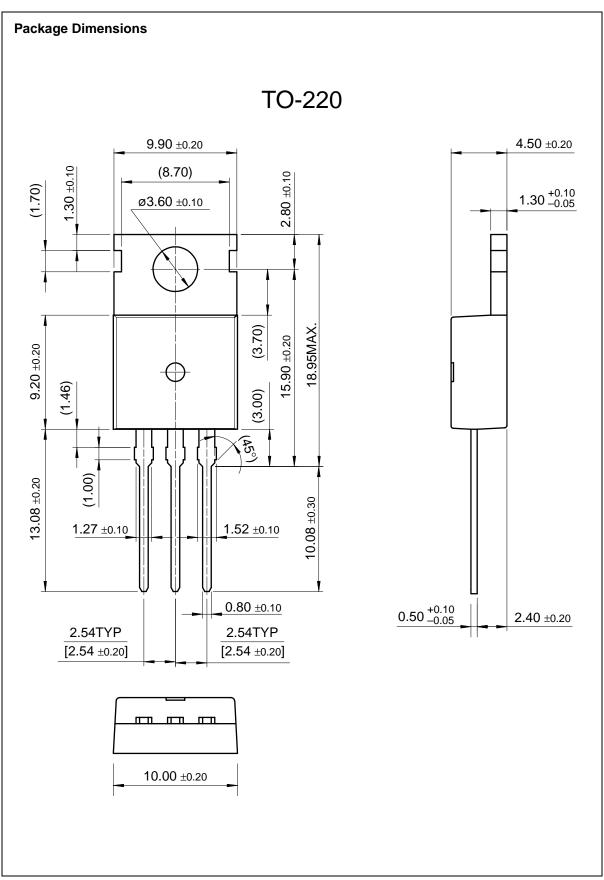






Body Diode Reverse Current





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